

| Application/Control No. | Applicant(s)/Patent under Reexamination | |
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| 10/064,816 | LIN, HOU-YUAN | |
| Examiner | Art Unit | |
| Brian R. Peugh | 2187 | |

| SEARCHED | | | | | |
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| Class | Subclass | Date | Examiner | | |
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| INTERFERENCE SEARCHED | | | | |
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| SEARCH NOTES (INCLUDING SEARCH STRATEGY) | | | |
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| | DATE | EXMR | |
| IEEE search | 5/20/2005 | BRP | |
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